

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/595,157 | | Applicant(s)/Patent Under Reexamination TAKENAKA ET AL. | |
| | Examiner John L. Goff | | Art Unit 1791 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,560,844 | 05-2003 | Pommer, Richard J. | 29/466 |
| * | B | US-4,614,559 | 09-1986 | Shirasawa et al. | 156/182 |
| * | C | US-2005/0230072 | 10-2005 | Levit, Mikhail R. | 162/146 |
| * | D | US-4,180,608 | 12-1979 | Del, Joseph A. | 428/196 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-----------------|----------------|
| | N | JP 57011026 A | 01-1982 | Japan | IKEGUCHI et al. | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.